

Yoshi Ohno
NIST Fellow, Sensor Science Division, NIST

Yoshi Ohno received his Ph.D. in engineering from Kyoto University, Japan. He started his career at Panasonic in Osaka, and joined NIST in 1992. He served as Group Leader for Optical Sensor Group from 2003 to 2012, and appointed as NIST Fellow in 2010. He has wide range of research in photometry, metrology, and color quality of light sources. Ohno is a Fellow of IES, and very active in national and international standardization work in IES, ANSI, and CIE. He is known as the primary author of LM-79 and ANSI C78.377. He led development of CIE S025 Test Method for LED lamps, LED luminaires and LED modules (2015), and now serves as President of CIE.